## Notice of References Cited Application/Control No. 10/790,492 Examiner Toniae M. Thomas Applicant(s)/Patent Under Reexamination ZHENG ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Hausemann et al., "Rapid Vapor Deposition of Highly Conformal Silica Nanolaminates," Science, Vol. 298, October 11, 2002, pages 402-406.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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